

# March 2015

# FDD8874 / FDU8874

# N-Channel PowerTrench® MOSFET **30V**, **116A**, **5.1m** $\Omega$

### **General Description**

This N-Channel MOSFET has been designed specifically to improve the overall efficiency of DC/DC converters using either synchronous or conventional switching PWM controllers. It has been optimized for low gate charge, low r<sub>DS(ON)</sub> and fast switching speed.

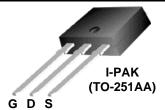
# **Applications**

DC/DC converters

**Features** 

- $r_{DS(ON)} = 5.1 \text{m}\Omega$ ,  $V_{GS} = 10 \text{V}$ ,  $I_D = 35 \text{A}$
- $r_{DS(ON)} = 6.4 \text{m}\Omega$ ,  $V_{GS} = 4.5 \text{V}$ ,  $I_D = 35 \text{A}$
- High performance trench technology for extremely low r<sub>DS(ON)</sub>
- · Low gate charge
- · High power and current handling capability
- · RoHS Compliant







# **MOSFET Maximum Ratings** $T_C = 25$ °C unless otherwise noted

Symbol	Parameter	Ratings	Units
V <sub>DSS</sub>	Drain to Source Voltage	30	V
$V_{GS}$	Gate to Source Voltage	±20	V
	Drain Current		
	Continuous (T <sub>C</sub> = 25°C, V <sub>GS</sub> = 10V) (Note 1)	116	Α
$I_D$	Continuous (T <sub>C</sub> = 25°C, V <sub>GS</sub> = 4.5V) (Note 1)	103	Α
	Continuous ( $T_{amb} = 25^{\circ}C$ , $V_{GS} = 10V$ , with $R_{\theta JA} = 52^{\circ}C/W$ )	18	Α
	Pulsed	Figure 4	Α
E <sub>AS</sub>	Single Pulse Avalanche Energy (Note 2)	240	mJ
D	Power dissipation	110	W
$P_{D}$	Derate above 25°C	0.73	W/°C
T <sub>J</sub> , T <sub>STG</sub>	Operating and Storage Temperature	-55 to 175	°C

### **Thermal Characteristics**

$R_{\theta JC}$	Thermal Resistance Junction to Case TO-252, TO-251	1.36	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, TO-251	100	°C/W
$R_{\theta JA}$	Thermal Resistance Junction to Ambient TO-252, 1in <sup>2</sup> copper pad area	52	°C/W

# **Package Marking and Ordering Information**

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDD8874	FDD8874	TO-252AA	13"	16mm	2500 units
FDU8874	FDU8874	TO-251AA	Tube	N/A (Tube)	75 units

# **Electrical Characteristics** $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter	Test C	onditions	Min	Тур	Max	Units
Off Chara	acteristics						
B <sub>VDSS</sub>	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_C$	<sub>3S</sub> = 0V	30	-	-	V
	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 24V		-	-	1	
IDSS Zero Gate voltage Drain Current	$V_{GS} = 0V$	$T_{\rm C} = 150^{\rm o}{\rm C}$	-	-	250	μΑ	
I <sub>GSS</sub>	Gate to Source Leakage Current V <sub>GS</sub> = ±20V		•	-	-	±100	nA

### **On Characteristics**

V <sub>GS(TH)</sub>	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}$ , $I_D = 250\mu A$	1.2	-	2.5	V
r <sub>DS(ON)</sub>		$I_D = 35A, V_{GS} = 10V$	-	0.0042	0.0051	0
	Drain to Source On Resistance	$I_D = 35A, V_{GS} = 4.5V$	-	0.0052	0.0064	
	Diam to oddiec on registance	$I_D = 35A, V_{GS} = 10V,$ $T_J = 175^{\circ}C$	-	0.0069	0.0083	32

### **Dynamic Characteristics**

C <sub>ISS</sub>	Input Capacitance	45)/ )/ 0)/	-	2990	-	pF
C <sub>OSS</sub>	Output Capacitance	V <sub>DS</sub> = 15V, V <sub>GS</sub> = 0V, f = 1MHz	-	585	-	pF
C <sub>RSS</sub>	Reverse Transfer Capacitance	1 - 1101112	-	340	-	pF
$R_{G}$	Gate Resistance	$V_{GS} = 0.5V$ , $f = 1MHz$	-	2.0	-	Ω
$Q_{g(TOT)}$	Total Gate Charge at 10V	V <sub>GS</sub> = 0V to 10V	-	54	72	nC
$Q_{g(5)}$	Total Gate Charge at 5V	$V_{GS} = 0V \text{ to } 5V$	-	29	38	nC
$Q_{g(TH)}$	Threshold Gate Charge	$V_{GS} = 0V \text{ to } 1V$ $V_{DD} = 15V$ $I_{D} = 35A$	-	3.0	4.0	nC
$Q_{gs}$	Gate to Source Gate Charge $I_{g} = 35A$		-	8.0	-	nC
Q <sub>gs2</sub>	Gate Charge Threshold to Plateau	.g = 1.511# t	-	5.0	-	nC
$Q_{gd}$	Gate to Drain "Miller" Charge		-	10	-	nC

# **Switching Characteristics** (V<sub>GS</sub> = 10V)

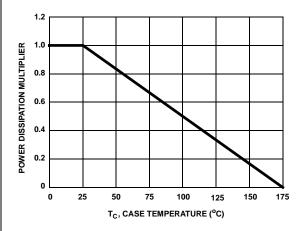
t <sub>ON</sub>	Turn-On Time		-	-	156	ns
t <sub>d(ON)</sub>	Turn-On Delay Time	1	-	9	-	ns
t <sub>r</sub>	Rise Time	V <sub>DD</sub> = 15V, I <sub>D</sub> = 35A	-	96	-	ns
t <sub>d(OFF)</sub>	Turn-Off Delay Time	$V_{GS} = 10V, R_{GS} = 4.7\Omega$		47	-	ns
t <sub>f</sub>	Fall Time	1	-	37	-	ns
t <sub>OFF</sub>	Turn-Off Time	1	-	-	126	ns

### **Drain-Source Diode Characteristics**

V <sub>SD</sub>	Source to Drain Diode Voltage	I <sub>SD</sub> = 35A	i	-	1.25	V
	7 <sub>SD</sub> Source to Drain Diode voltage	I <sub>SD</sub> = 15A	ı	-	1.0	V
t <sub>rr</sub>	Reverse Recovery Time	$I_{SD} = 35A$ , $dI_{SD}/dt = 100A/\mu s$	-	-	32	ns
$Q_{RR}$	Reverse Recovered Charge	$I_{SD} = 35A$ , $dI_{SD}/dt = 100A/\mu s$	ı	-	18	nC

Notes: 1: Package current limitation is 35A. 2: Starting  $T_J = 25^{\circ}C$ , L = 0.61mH,  $I_{AS} = 28A$ ,  $V_{DD} = 27V$ ,  $V_{GS} = 10V$ .





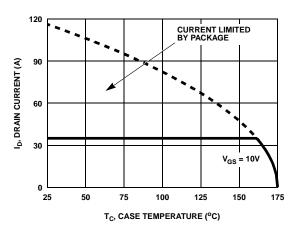


Figure 1. Normalized Power Dissipation vs Case Temperature

Figure 2. Maximum Continuous Drain Current vs Case Temperature

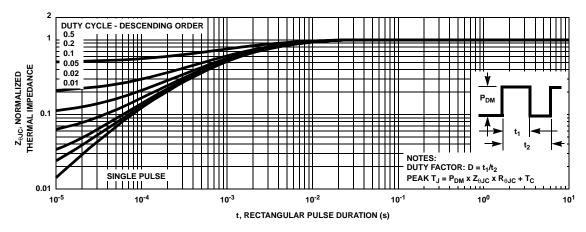


Figure 3. Normalized Maximum Transient Thermal Impedance

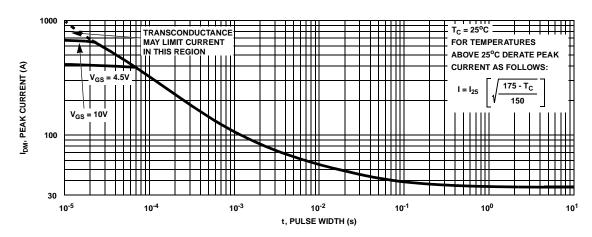
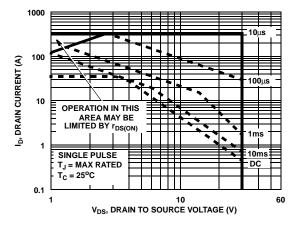


Figure 4. Peak Current Capability

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100

If R = 0

t<sub>AV</sub> = (L)(I<sub>AS</sub>)/(1.3\*RATED BV<sub>DSS</sub> - V<sub>DD</sub>)

t<sub>AV</sub> = (L/R)In[(I<sub>AS</sub>\*R)/(1.3\*RATED BV<sub>DSS</sub> - V<sub>DD</sub>) +1]

100

STARTING T<sub>J</sub> = 150°C

11

10.1

1 10

100

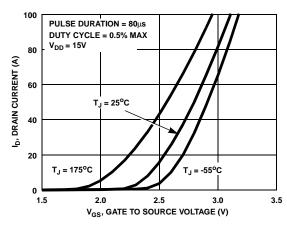
100

Figure 5. Forward Bias Safe Operating Area

NOTE: Refer to Fairchild Application Notes AN7514 and AN7515

Figure 6. Unclamped Inductive Switching

Capability



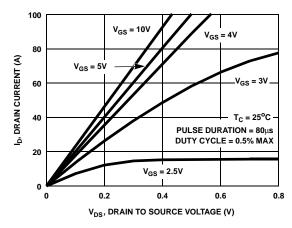
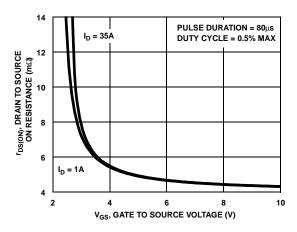


Figure 7. Transfer Characteristics

Figure 8. Saturation Characteristics



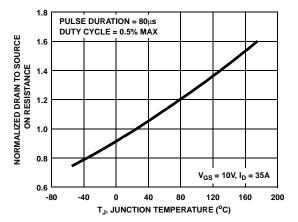


Figure 9. Drain to Source On Resistance vs Gate Voltage and Drain Current

Figure 10. Normalized Drain to Source On Resistance vs Junction Temperature

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# Typical Characteristics $T_C = 25^{\circ}C$ unless otherwise noted

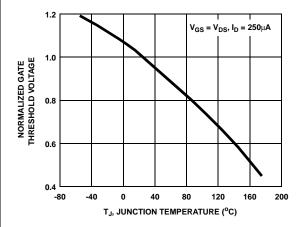


Figure 11. Normalized Gate Threshold Voltage vs
Junction Temperature

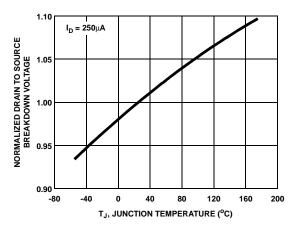


Figure 12. Normalized Drain to Source Breakdown Voltage vs Junction Temperature

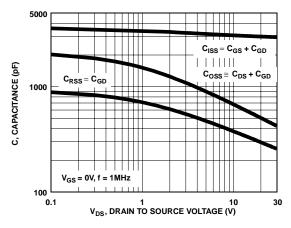


Figure 13. Capacitance vs Drain to Source Voltage

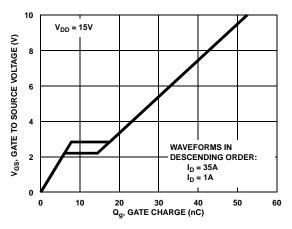


Figure 14. Gate Charge Waveforms for Constant Gate Current

# **Test Circuits and Waveforms**

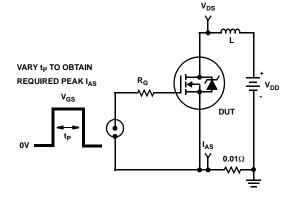


Figure 15. Unclamped Energy Test Circuit

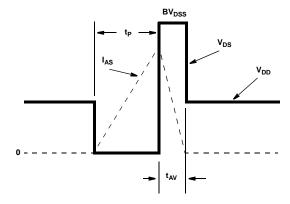


Figure 16. Unclamped Energy Waveforms

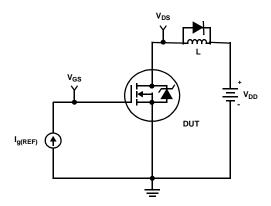


Figure 17. Gate Charge Test Circuit

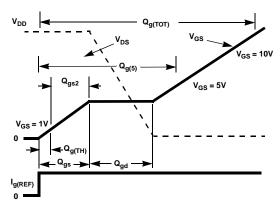


Figure 18. Gate Charge Waveforms

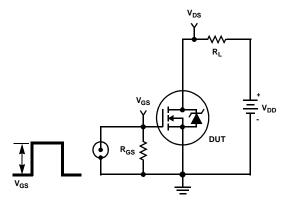


Figure 19. Switching Time Test Circuit

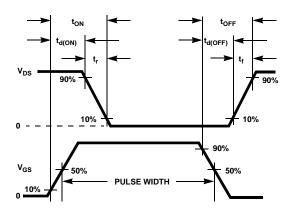


Figure 20. Switching Time Waveforms

# Thermal Resistance vs. Mounting Pad Area

The maximum rated junction temperature,  $T_{JM}$ , and the thermal resistance of the heat dissipating path determines the maximum allowable device power dissipation,  $P_{DM}$ , in an application. Therefore the application's ambient temperature,  $T_A$  (°C), and thermal resistance  $R_{\theta JA}$  (°C/W) must be reviewed to ensure that  $T_{JM}$  is never exceeded. Equation 1 mathematically represents the relationship and serves as the basis for establishing the rating of the part.

$$P_{DM} = \frac{(T_{JM} - T_A)}{R_{\theta JA}} \tag{EQ. 1}$$

In using surface mount devices such as the TO-252 package, the environment in which it is applied will have a significant influence on the part's current and maximum power dissipation ratings. Precise determination of  $\mathsf{P}_{\mathsf{DM}}$  is complex and influenced by many factors:

- Mounting pad area onto which the device is attached and whether there is copper on one side or both sides of the board.
- 2. The number of copper layers and the thickness of the board.
- 3. The use of external heat sinks.
- 4. The use of thermal vias.
- 5. Air flow and board orientation.
- For non steady state applications, the pulse width, the duty cycle and the transient thermal response of the part, the board and the environment they are in.

Fairchild provides thermal information to assist the designer's preliminary application evaluation. Figure 21 defines the  $R_{\theta JA}$  for the device as a function of the top copper (component side) area. This is for a horizontally positioned FR-4 board with 1oz copper after 1000 seconds of steady state power with no air flow. This graph provides the necessary information for calculation of the steady state junction temperature or power dissipation. Pulse applications can be evaluated using the Fairchild device Spice thermal model or manually utilizing the normalized maximum transient thermal impedance curve.

Thermal resistances corresponding to other copper areas can be obtained from Figure 21 or by calculation using Equation 2 or 3. Equation 2 is used for copper area defined in inches square and equation 3 is for area in centimeters square. The area, in square inches or square centimeters is the top copper area including the gate and source pads.

$$R_{\Theta JA} = 33.32 + \frac{23.84}{(0.268 + Area)}$$
 (EQ. 2)

Area in Inches Squared

$$R_{\theta JA} = 33.32 + \frac{154}{(1.73 + Area)}$$
 (EQ. 3)

Area in Centimeters Squared

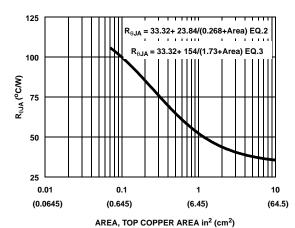
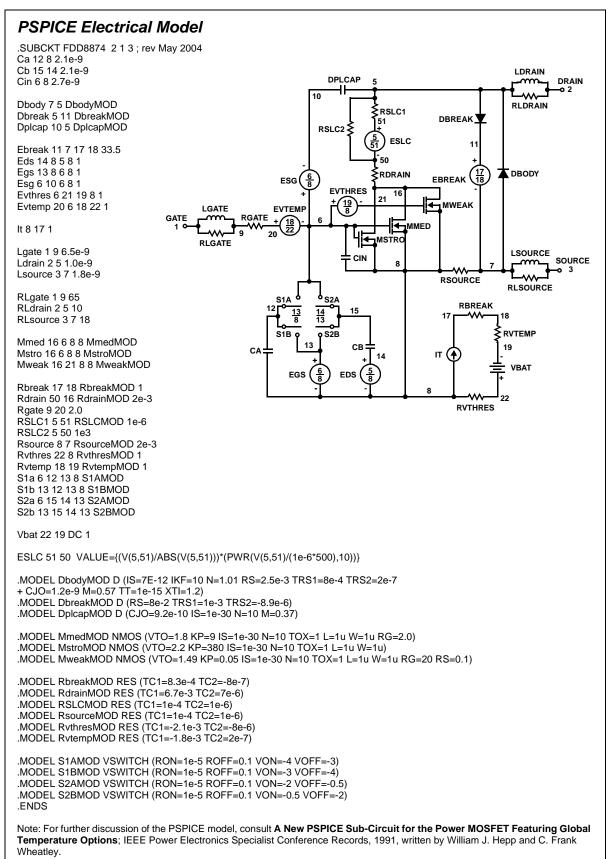


Figure 21. Thermal Resistance vs Mounting Pad Area



### SABER Electrical Model rev May 2004 template FDD8874 n2,n1,n3 electrical n2,n1,n3 var i iscl dp..model dbodymod = (isl=7e-12,ikf=10,nl=1.01,rs=2.5e-3,trs1=8e-4,trs2=2e-7,cjo=1.2e-9,m=0.57,tt=1e-15,xti=1.2) dp..model dbreakmod = (rs=8e-2,trs1=1e-3,trs2=-8.9e-6) dp..model dplcapmod = (cjo=9.2e-10,isl=10e-30,nl=10,m=0.37) m..model mmedmod = $(type=_n, vto=1.8, kp=9, is=1e-30, tox=1)$ m..model mstrongmod = (type= n,vto=2.2,kp=380,is=1e-30, tox=1) m..model mweakmod = (type=\_n,vto=1.49,kp=0.05,is=1e-30, tox=1,rs=0.1) LDRAIN sw\_vcsp..model s1amod = (ron=1e-5,roff=0.1,von=-4,voff=-3) **DPLCAP** DRAIN sw\_vcsp..model s1bmod = (ron=1e-5,roff=0.1,von=-3,voff=-4) 10 sw\_vcsp..model s2amod = (ron=1e-5,roff=0.1,von=-2,voff=-0.5) RLDRAIN sw\_vcsp..model s2bmod = (ron=1e-5,roff=0.1,von=-0.5,voff=-2) RSLC1 c.ca n12 n8 = 2.1e-951 RSLC2 € c.cb n15 n14 = 2.1e-9ISCI c.cin n6 n8 = 2.7e-9DBREAK dp.dbody n7 n5 = model=dbodymod RDRAIN <u>6</u>8 dp.dbreak n5 n11 = model=dbreakmod **FSG** DBODY dp.dplcap n10 n5 = model=dplcapmod **EVTHRES** (<u>19</u>) **MWEAK** LGATE **EVTEMP** spe.ebreak n11 n7 n17 n18 = 33.5 GATE 18 22 EBREAK spe.eds n14 n8 n5 n8 = 1 MMED spe.egs n13 n8 n6 n8 = 1 **←**MSTRC RLGATE spe.esg n6 n10 n6 n8 = 1 LSOURCE spe.evthres n6 n21 n19 n8 = 1 CIN SOURCE spe.evtemp n20 n6 n18 n22 = 1 RSOURCE RLSOURCE i.it n8 n17 = 1 RBREAK I.lgate n1 n9 = 6.5e-9I.Idrain n2 n5 = 1.0e-9**₹**RVTEMP oS2B I.Isource n3 n7 = 1.8e-919 СА IT (♠ 14 res.rlgate n1 n9 = 65 VBAT res.rldrain n2 n5 = 10 **EGS EDS** res.rlsource n3 n7 = 18 m.mmed n16 n6 n8 n8 = model=mmedmod, l=1u, w=1u **RVTHRES** m.mstrong n16 n6 n8 n8 = model=mstrongmod, l=1u, w=1u m.mweak n16 n21 n8 n8 = model=mweakmod. l=1u, w=1u res.rbreak n17 n18 = 1, tc1=8.3e-4,tc2=-8e-7 res.rdrain n50 n16 = 2e-3, tc1=6.7e-3,tc2=7e-6 res.rgate n9 n20 = 2.0res.rslc1 n5 n51 = 1e-6, tc1=1e-4,tc2=1e-6 res.rslc2 n5 n50 = 1e3res.rsource n8 n7 = 2e-3, tc1=1e-4,tc2=1e-6 res.rvthres n22 n8 = 1, tc1=-2.1e-3,tc2=-8e-6 res.rvtemp n18 n19 = 1. tc1=-1.8e-3.tc2=2e-7sw\_vcsp.s1a n6 n12 n13 n8 = model=s1amod sw\_vcsp.s1b n13 n12 n13 n8 = model=s1bmod sw\_vcsp.s2a n6 n15 n14 n13 = model=s2amod sw\_vcsp.s2b n13 n15 n14 n13 = model=s2bmod v.vbat n22 n19 = dc=1 equations { iscl: v(n51,n50) = ((v(n5,n51)/(1e-9+abs(v(n5,n51))))\*((abs(v(n5,n51)\*1e6/500))\*\* 10))

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# **PSPICE Thermal Model** JUNCTION REV 23 May 2004 FDD8874T CTHERM1 TH 6 1.9e-3 CTHERM2 6 5 2.8e-3 CTHERM3 5 4 3.5e-3 RTHERM1 CTHERM1 CTHERM4 4 3 3.6e-3 CTHERM5 3 2 4.0e-3 CTHERM6 2 TL 1.6e-2 RTHERM1 TH 6 3.8e-2 RTHERM2 6 5 5.0e-2 RTHERM3 5 4 1.0e-1 RTHERM2 CTHERM2 RTHERM4 4 3 1.8e-1 RTHERM5 3 2 3.5e-1 RTHERM6 2 TL 3.7e-1 5 SABER Thermal Model SABER thermal model FDD8874T RTHERM3 CTHERM3 template thermal\_model th tl thermal\_c th, tl ctherm.ctherm1 th 6 =1.9e-3 ctherm.ctherm2 6 5 = 2.8e-3 ctherm.ctherm3 5 4 =3.5e-3 ctherm.ctherm4 4 3 =3.6e-3 ctherm.ctherm5 3 2 =4.0e-3 RTHERM4 CTHERM4 ctherm.ctherm6 2 tl =1.6e-2 rtherm.rtherm1 th 6 = 3.8e-2 rtherm.rtherm2 6 5 =5.0e-2 3 rtherm.rtherm3 5 4 =1.0e-1 rtherm.rtherm4 4 3 =1.8e-1 rtherm.rtherm5 3 2 = 3.5e-1 RTHERM5 CTHERM5 rtherm.rtherm6 2 tl =3.7e-1 2 RTHERM6 CTHERM6 CASE tl







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Deminition of Terms		
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